

“Digital Communications Test and Measurement” book published by Dennis Derickson and Marcus Mueller.

Dennis Derickson (Cal Poly) and Marcus Mueller (Agilent) recently edited the book **“Digital Communications Test and Measurement: High Speed Physical Layer Characterization”**, ISBN-13:978-0-13-220910-6, Prentice Hall 2008. This 900 page book covers the topics of bit error ratio measurement, high speed digital waveform analysis, time jitter, and characterization of the physical interconnection structures in printed circuit board environments. The contributors to this work come from major test and measurement equipment vendors (Agilent and Tektronix), component manufacturers and researchers in the university setting. The formal book launch occurred at the *2008 Design Con* exposition in Santa Clara, California on Feb 5.

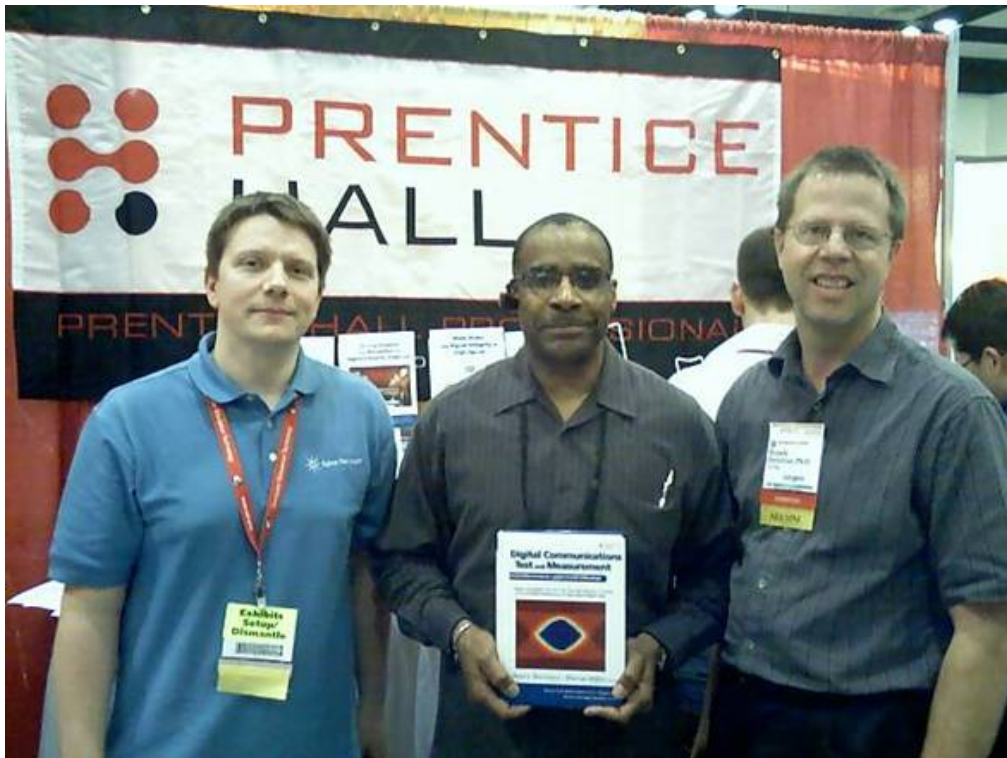


Figure 1. (left) Marcus Mueller (Agilent Technologies), (center) Bernard Goodwin (Prentice Hall) and (right) Dennis Derickson (Cal Poly) at the *2008 Design Con* conference introduction of “Digital Communications Test and Measurement”.